

IEC SYSTEM FOR MUTUAL RECOGNITION OF TEST CERTIFICATES FOR ELECTRICAL EQUIPMENT (IECEE)
CB SCHEME

CB TEST CERTIFICATE

Product

Mother board

Name and address of the applicant

INTEL CORPORATION
2200 Mission College Blvd Santa Clara, CA 95054 USA

Name and address of the manufacturer

INTEL CORPORATION
2200 Mission College Blvd Santa Clara, CA 95054 USA

Name and address of the factory

MAINTEK COMPUTER (SUZHOU) CO LTD
233 JIN FENG RD NEW DISTRICT SUZHOU JIANGSU 215011
CHINA

Note: When more than one factory, please report on page 2

 Additional Information on page 2

Ratings and principal characteristics

19Vdc

Trademark / Brand (if any)

INTEL



Type of Customer's Testing Facility (CTF) Stage used

Model / Type Ref.

NUC11TNB, xNUC11xTNBx (where x can be a combination of alphanumeric characters or blank)

Additional information (if necessary may also be reported on page 2)

Additionally evaluated to EN 60950-1: 2006 / A11: 2009 / A1: 2010 / A12: 2011 / A2: 2013
National Difference specified in the CB Test Report Additional Information on page 2

A sample of the product was tested and found to be in conformity with

IEC 60950-1:2005/AMD1:2009, IEC 60950-1:2005/AMD2:2013,
IEC 60950-1:2005

As shown in the Test Report Ref. No. which forms part of this Certificate

ASL20080622 issued on 2020-10-05

This CB Test Certificate is issued by the National Certification Body



- UL (US), 333 Pfingsten Rd IL 60062, Northbrook, USA
- UL (Demko), Borupvang 5A DK-2750 Ballerup, DENMARK
- UL (JP), Marunouchi Trust Tower Main Building 6F, 1-8-3 Marunouchi, Chiyoda-ku, Tokyo 100-0005, JAPAN
- UL (CA), 7 Underwriters Road, Toronto, M1R 3B4 Ontario, CANADA

For full legal entity names see www.ul.com/ncbnames

Date: 2020-10-13

Signature:

Jan-Erik Storgaard